
**Information technology — Automatic
identification and data capture
techniques — Direct Part Mark (DPM)
Quality Guideline**

*Technologies de l'information — Techniques automatiques
d'identification et de capture de données — Ligne directrice de
qualité du marquage direct sur pièce (DPM)*





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Foreword

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This document was prepared by Joint Technical Committee ISO/TC JTC 1, *Information Technology*, Subcommittee SC 31, *Automatic identification and data capture techniques*.

This first edition cancels and replaces ISO/IEC TR 29158:2011, which has been technically revised.

The main changes compared to the previous edition are as follows:

- inclusion of continuous grading;
- expanded grading levels for minimum reflectance (R_{target});
- inclusion of a tilted lighting and camera position;
- reorganized proposed lighting options.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.